



Part of #1

Sheet 1 of 1

FORM PTO-1449

U.S. Department of Commerce  
Patent & Trademark OfficeAttorney Docket No.  
2285/51302Serial No.  
10/052,306**INFORMATION DISCLOSURE  
STATEMENT**  
(Use several sheets if necessary)

Applicant: Yumiko KAWANO, et al.

Filing Date  
January 18, 2002

Group

**U.S. PATENT DOCUMENTS**

| Examiner Initial |    | Document Number | Date | Name | Class | Sub-Class | Filing Date (if appropriate) |
|------------------|----|-----------------|------|------|-------|-----------|------------------------------|
|                  | AA |                 |      |      |       |           |                              |
|                  | AB |                 |      |      |       |           |                              |
|                  | AC |                 |      |      |       |           |                              |
|                  | AD |                 |      |      |       |           |                              |
|                  | AE |                 |      |      |       |           |                              |
|                  | AF |                 |      |      |       |           |                              |
|                  | AG |                 |      |      |       |           |                              |
|                  | AH |                 |      |      |       |           |                              |
|                  | AI |                 |      |      |       |           |                              |

**FOREIGN PATENT DOCUMENTS**

| Examiner Initial |    | Document Number | Date    | Name                | Class | Sub-Class | TRANSLATION |    |
|------------------|----|-----------------|---------|---------------------|-------|-----------|-------------|----|
|                  |    |                 |         |                     |       |           | Yes         | No |
| ER               | AK | 64-501          | 01/1989 | Japan               |       |           | No          |    |
|                  | AL | 0349695         | 01/90   | L'Air Liquide       |       |           | No          |    |
|                  | AM | 63-072881       | 04/88   | Toshiba Corporation |       |           | Abstract    |    |
|                  | AN | 09-186110       | 07/97   | Tokyo Electron      |       |           | Abstract    |    |
|                  | AO | 05-078846       | 03/93   | Osaka Gas Co.       |       |           | Abstract    |    |
|                  | AP | 05-226282       | 09/1993 | NEC Corporation     |       |           | Abstract    |    |
| ER               | AQ | 64-068474       | 09/1989 | Tokyo Electron      |       |           | Abstract    |    |

**OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, etc.)**

|    |    |  |  |  |  |  |  |
|----|----|--|--|--|--|--|--|
| CK | AR | S.C. SUN, et al. "Characterization of Diffusion Barrier Properties of CVD and PVD Tungsten Nitride Thin Films" VMIC Conference, June 18-20, 1996   |  |  |  |  |  |
| ER | AS | Toshiya SUZUKI, et al., "Comparison of CVD TiN, PECVD WN <sub>x</sub> , and CVD W-Si-N as Upper Electrode Materials for Ta <sub>2</sub> O <sub>5</sub> DRAM Capacitors" Conference Proceedings ULSI XIII, 1998 |  |  |  |  |  |
|    | AT |  |  |  |  |  |  |

EXAMINER

DATE CONSIDERED

12/11/02

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication.

